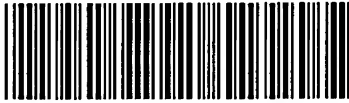


Search Notes

Application/Control No.

10/783,485

Examiner

David Sample

Applicant(s)/Patent under
Reexamination

CHEN ET AL.

Art Unit

1755

SEARCHED

Class	Subclass	Date	Examiner
502	152	7/5/2006	<i>DS</i>
	154		
	156		
	161		
	170		
	171		
	172	7/5/2006	<i>DS</i>

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East searched	7/5/2006	<i>DS</i>
Inventor name search in PALM	7/8/2006	<i>DS</i>